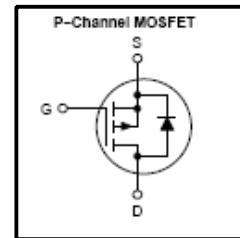


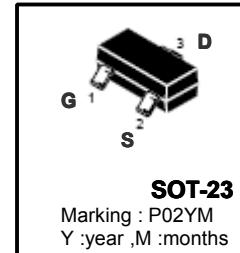
Features

- -3.2A, -20V, $R_{DS(on)}$ (Max 85mΩ)@ $V_{GS}=-4.5V$
- -1.5 V Rated for Low Voltage Gate Drive
- SOT-23 Surface Mount for Small Footprint
- Single Pulse Avalanche Energy Rated
- Halogen-free



General Description

This Power MOSFET is produced using Winsemi's advanced MOS technology. This latest technology has been especially designed to minimize on-state resistance, have a high rugged avalanche characteristics. This devices is specially well suited for Load/Power Management for Portables and Computing, Charging Circuits and Battery Protection



Absolute Maximum Ratings

Symbol	Parameter			Value	Units
V_{DSS}	Drain Source Voltage			-20	V
I_D	Continuous Drain Current(Note 1)	Steady State	$T_c=25^\circ C$	-2.4	A
			$T_c=85^\circ C$	-1.7	
		$t \leq 10s$	$T_c=25^\circ C$	-3.2	
P_D	Total Power Dissipation(Note 1)	Steady State	$T_c=25^\circ C$	0.73	W
			$t \leq 10s$	1.25	
I_D	Continuous Drain Current(Note 2)	Steady State	$T_c=25^\circ C$	-1.8	A
			$T_c=85^\circ C$	-1.3	
			$T_c=25^\circ C$	0.42	
I_{DM}	Drain Current Pulsed	$t=10s$		-7.5	A
V_{GS}	Gate to Source Voltage			± 8	V
ESD	ESD Capability (Note 3)	$C=100pF, R_s = 1500\Omega$		225	V
T_J, T_{stg}	Junction and Storage Temperature			-55~150	°C
T_L	Maximum lead Temperature for soldering purposes			260	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

Thermal Characteristics

Symbol	Parameter	Value			Units
		Min	Typ	Max	
R_{QJA}	Thermal Resistance, Junction-to-Ambient(Note 1)	-	-	170	°C/W
R_{QJA}	Thermal Resistance, Junction-to-Ambient(Note 1)			110	°C/W
R_{QJA}	Thermal Resistance, Junction-to-Ambient(Note 2)			300	°C/W

Note 1: Surface-mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces)

Note 2: Surface-mounted on FR4 board using the minimum recommended pad size.

Note 3: ESD Rating Information: HBM Class 0

Electrical Characteristics ($T_c = 25^\circ\text{C}$)

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit
Gate leakage current(Note 4)	I_{GSS}	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	± 100	nA
Drain cut-off current(Note 4)	I_{DSS}	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	-1	μA
Drain-source breakdown voltage	$V_{(BR)DSS}$	$I_D = -250 \mu\text{A}, V_{GS} = 0 \text{ V}$	-20	-	-	V
Gate threshold voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS} I_D = -250 \mu\text{A}$	-0.40	-0.72	-1.5	V
Drain-source ON resistance	$R_{DS(\text{ON})}$	$V_{GS} = -4.5 \text{ V}, I_D = -1.6 \text{ A}$	-	70	85	$\text{m}\Omega$
		$V_{GS} = -2.5 \text{ V}, I_D = -1.3 \text{ A}$		90	120	
		$V_{GS} = -1.8 \text{ V}, I_D = -0.9 \text{ A}$		112	200	
Forward Transconductance	g_{fs}	$V_{DS} = -5.0 \text{ V}, I_D = -2.3 \text{ A}$	-	75	-	S
Input capacitance	C_{iss}	$V_{DS} = -10 \text{ V},$ $V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	-	675	-	pF
Reverse transfer capacitance	C_{rss}		-	75	-	
Output capacitance	C_{oss}		-	100	-	
Switching time (Note 5)	Rise time	$V_{GS} = -4.5 \text{ V},$ $V_{DS} = -10 \text{ V},$ $I_D = -1.6 \text{ A},$ $R_G = 6.0 \Omega$	-	12.6	-	ns
	Turn-on time	t_{on}	-	7.5	-	
	Fall time	t_f	-	21.0	-	
	Turn-off time	t_{off}	-	30.2	-	
Total gate charge (gate-source plus gate-drain)	Q_g	$V_{GS} = -4.5 \text{ V},$ $V_{DS} = -10 \text{ V},$ $I_D = -1.6 \text{ A}$	-	7.5	8.5	nC
Gate-source charge	Q_{gs}		-	1.2	-	
Gate-drain ("miller") Charge	Q_{gd}		-	2.2	-	
Reverse Recovery Charge	R_G		-	6.5	-	Ω

Source-Drain Ratings and Characteristics ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit
Continuous drain reverse current	I_{DR}	-	-	-	-2.4	A
Pulse drain reverse current	I_{DRP}	-	-	-	-7.5	A
Forward voltage (diode)	V_{DSF}	$I_{DR} = -2.4 \text{ A}, V_{GS} = 0 \text{ V}$	-	-0.82	-1.2	V
Reverse recovery time	t_{rr}	$I_{DR} = -2.4 \text{ A},$ $V_{GS} = 0 \text{ V},$ $dI_{DR} / dt = 100 \text{ A} / \mu\text{s}$	-	12.8	15	ns
Charge Time	t_a			9.9		ns
Discharge Time	t_b			3.0		ns
Reverse recovery charge	Q_{rr}		-	1008	-	μC

Note 4: Pulse Test: Pulse Width $\leq 300 \mu\text{s}$, Duty Cycle 3.2%.

Note 5: Switching characteristics are independent of operating junction temperature.

This transistor is an electrostatic sensitive device

Please handle with caution

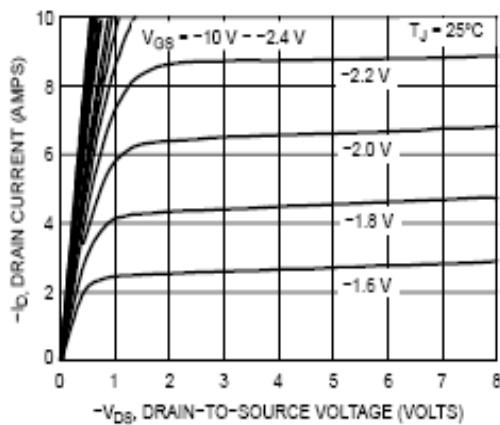


Fig. 1 On-State Characteristics

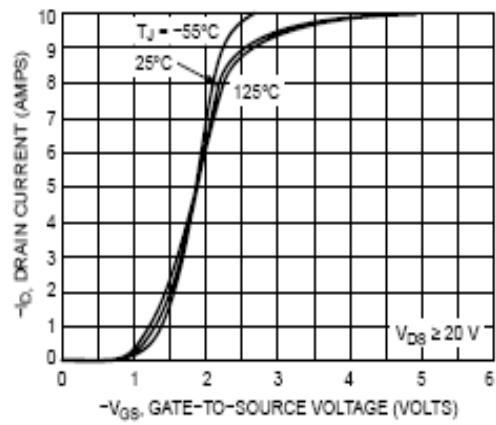


Fig. 2 Transfer Current Characteristics

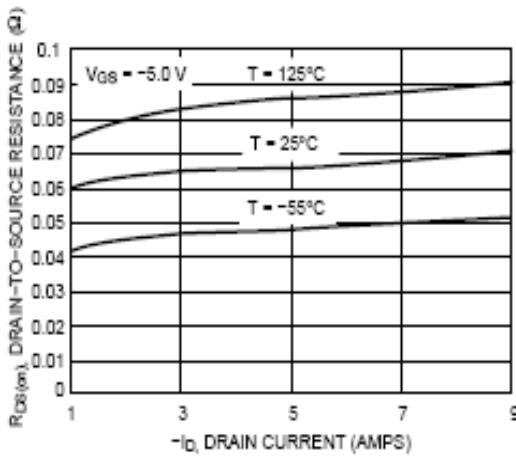


Fig. 3 On-Resistance vs. Drain Current and Temperature

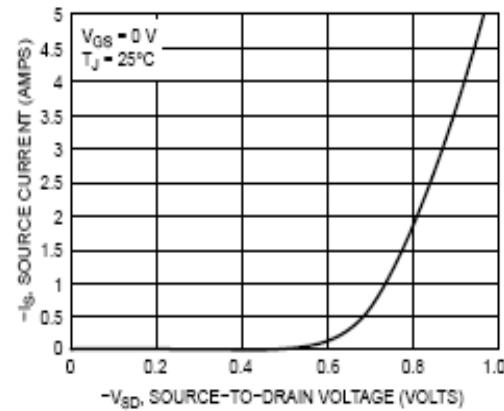


Fig. 4 Diode Forward Voltage vs. Current

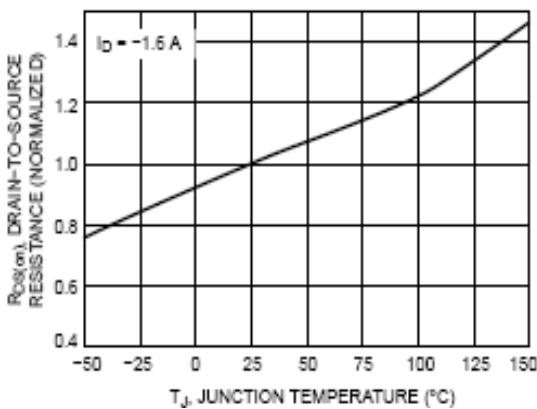


Fig. 5 On-Resistance Variation vs Junction Temperature

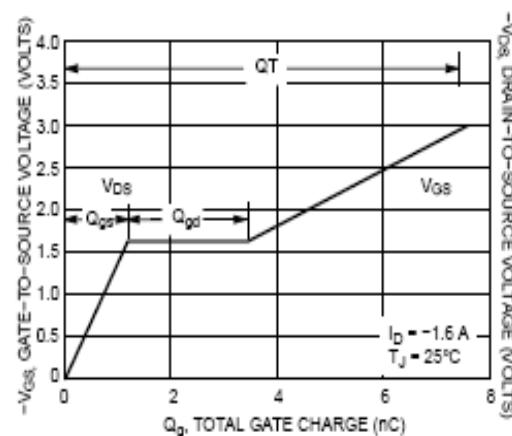
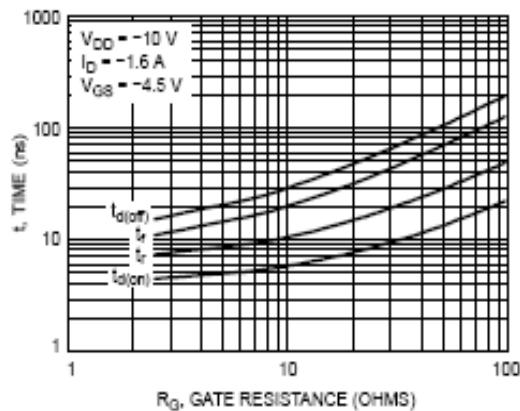
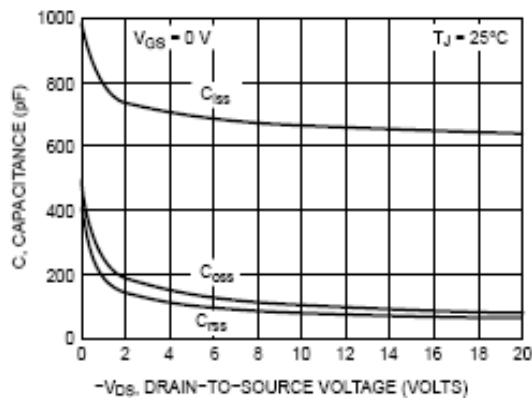


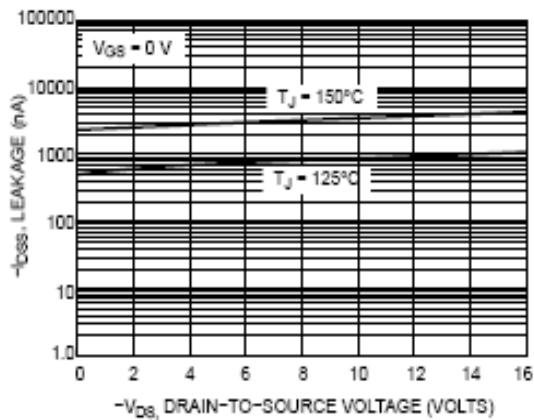
Fig. 6 Gate Charge Characteristics



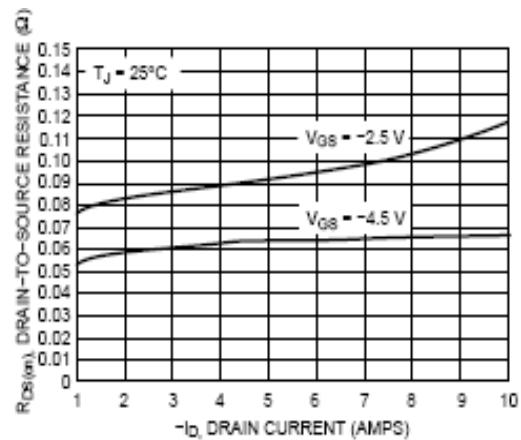
**Fig.7 Resistive Switching Time Variation
vs. Gate Resistance**



**Fig.8 Maximum Drain Current vs Case
Temperature**



**Fig.9 Drain-to-Source Leakage Current
vs. Voltage**



**Fig.10 On-Resistance vs. Drain Current and
Temperature**

SOT-23 Package Dimension

